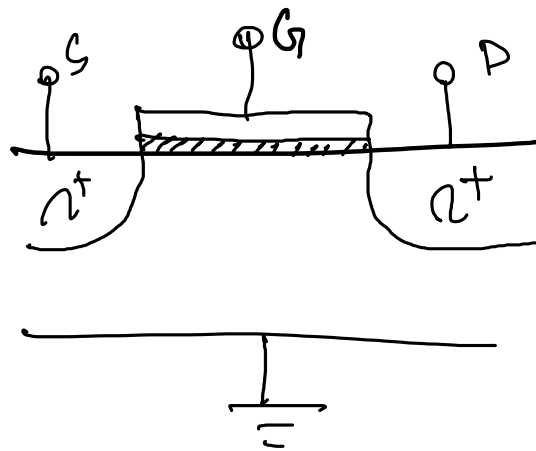


Drain Current equation in three regions of operation:-

Cutoff region : ($V_{GS} < V_{th}$)

* In the cutoff region where the gate to source voltage $V_{GS} < V_{th}$, we don't have the channel formed underneath the gate oxide layer.

* source and Drain are not electrically connected, there is zero current through the device.



$$(V_G < V_{th})$$

no channel

$$I_D \approx 0$$

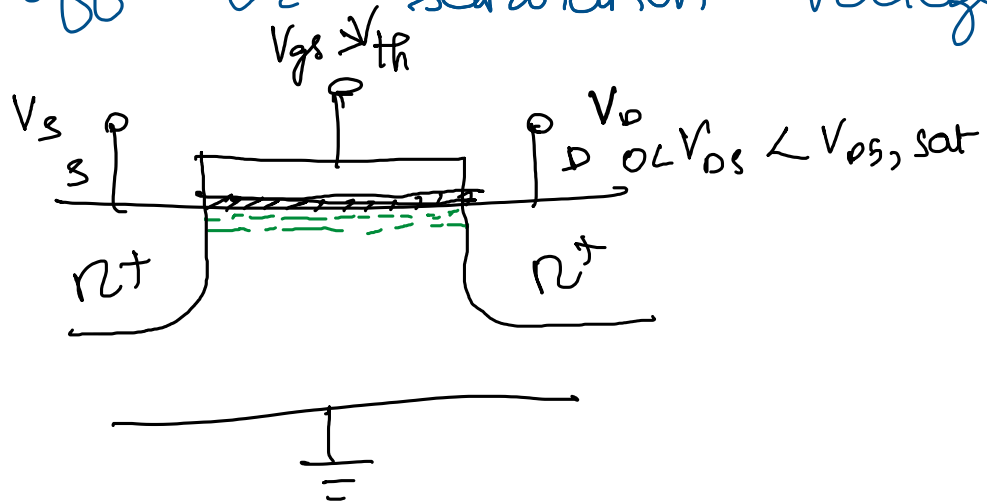
Triode / Linear / Active region:-

$$V_{GS} > V_{th} \text{ and } 0 < V_{DS} < V_{DS,sat}; V_{DS,sat} = V_{GS} - V_{th}$$

* uniform channel is formed underneath the gate oxide layer

* I_D , drain current is a strong fn of V_{GS} and a weak fn of V_{DS} .

* In this region of operation, the gate to source voltage is greater than a threshold voltage but less than the pinch off or saturation voltage.



Eqn for I_D :

$$Q_{channel} = C_g (V_{gc} - V_{th})$$

$$C_g = \frac{\epsilon_{ox}}{t_{ox}} WL = C_{ox} WL$$

$$V_{gc} = \frac{V_{gs} + V_{gd}}{2}$$

$V_{gs} \rightarrow$ gate to source voltage

$V_{gd} \rightarrow$ gate to drain voltage

$$V_{gd} = V_{gs} - V_{ds}$$

$$V_{gc} = \frac{V_{gs} + V_{gs} - V_{ds}}{2} = V_{gs} - \frac{V_{ds}}{2}$$

Sub. V_{gs} and C_g in channel eqn,

$$Q_{\text{channel}} = C_{ox} WL \left(V_{gs} - V_{th} - \frac{V_{ds}}{2} \right)$$

$$I_D = \frac{Q_{\text{channel}}}{t} ; \quad t = \frac{L}{v} \rightarrow \text{velocity}$$

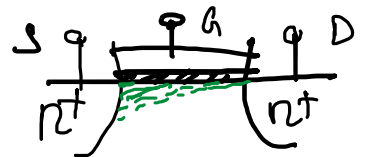
$$v = \mu E ; \quad E = \frac{V_{ds}}{L}$$

$$I_D = \frac{C_{ox} WL \left(V_{gs} - V_{th} - \frac{V_{ds}}{2} \right)}{\frac{L}{\mu \frac{V_{ds}}{L}}}$$

$$I_D = \mu C_{ox} \frac{W}{L} \left(V_{gs} - V_{th} - \frac{V_{ds}}{2} \right) V_{ds}$$

Saturation region: $V_{gs} > V_{th}$ and $V_{ds} \geq V_{ds, \text{sat}}$
 here $V_{ds} = V_{gs} - V_{th}$, Sub. in I_D $V_{ds, \text{sat}} = V_{gs} - V_{th}$

$$I_D = \mu C_{ox} \frac{W}{L} \left(V_{gs} - V_{th} - \frac{V_{gs} - V_{th}}{2} \right) (V_{gs} - V_{th})$$



$$I_D = \frac{1}{2} \mu C_{ox} \frac{W}{L} (V_{gs} - V_{th})^2 = \beta (V_{gs} - V_{th})^2$$